

PATENT

Docket No.: M4065.0215/P215

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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In re Patent Application of:
Eugene DeLaRosa et al.

Serial No.: 09/516,581

Filed: March 1, 2000

For: METHOD FOR MEASURING
REGISTRATION OF
OVERLAPPING MATERIAL
LAYERS OF AN INTEGRATED
CIRCUIT



Group Art Unit: Not Yet Assigned

Examiner: Not Yet Assigned

Assistant Commissioner for Patents
Washington, D.C. 20231

REQUEST FOR APPROVAL OF DRAWING CORRECTION

Dear Sir:

Applicants hereby request Examiner approval of the drawing corrections shown in red on the attached one (1) sheet, of Fig. 5, submitted herewith for filing in the above-identified Patent Application. The corrections remove unnecessary verbage and numerical information from Fig. 5.

Favorable consideration of the enclosed corrected drawing is respectfully requested.

Dated: April 27, 2000

Respectfully submitted,

By 

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